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Electrical Characterization, Modeling and Simulation of CMOS Memory Devices

Guest Editor

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Deadline for manuscript submissions:

closed (1 April 2022)

Message from the Guest Editor

This Special Issue aims to present studies on new materials and architectures for memory devices, conducted using methods of electrical characterization, modeling and device simulation and focused on consolidated themes such as non-volatile NAND flash and discrete-trap memories. Technological options for the near future, such as resistive RAM memories and one-transistor (1T)- and MIMCAP-based DRAMs, will also be considered.

- CMOS memory devices
- Device fabrication
- Modeling and numerical simulation
- Electrical material and device characterization
- One transistor (1T)-based DRAMs
- Metal-insulator-metal capacitors (MIMCAPs)
- Resistive memories (Re-RAMs)
- NAND flash memories
- Discrete-trap memories

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Message from the Editor-in-Chief

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